

<b>Notice of References Cited</b>	Application/Control No. 10/028,289	Applicant(s)/Patent Under Reexamination HA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,621,545	09-2003	Park et al.	349/141
	B	US-6,448,579	09-2002	Lim et al.	257/59
	C	US-6,384,889	05-2002	Miyachi et al.	349/143
	D	US-2002/0030769	03-2002	Bae, Sung Sik	349/43
	E	US-6,243,146	06-2001	Rho et al.	349/42
	F	US-6,172,729	01-2001	Ikeda, Munehiro	349/145
	G	US-5,739,880	04-1998	Suzuki et al.	349/110
	H	US-5,621,553	04-1997	Nishiguchi et al.	349/153
	I	US-4,723,838	02-1988	Aoki et al.	349/47
	J	US-4,206,471	06-1980	Hoffmann et al.	257/296
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP10090717	04-1998	Japan	Kataoka et al.	G02F 1/136
	O	JP11326949	11-1999	Japan	Kohei	G02F 1/136
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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